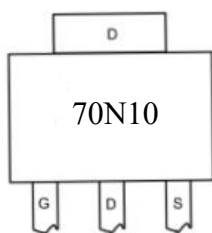


**Features**

- Split Gate Trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$

 B_{vds} **100V** **R_{dson}** **8.5mΩ** **I_D** **70A****Application**

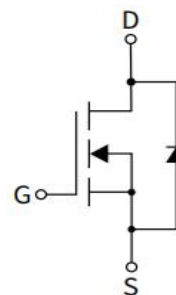
- DC-DC Converters
- Power management function
- Synchronous-rectification applications

RoHS**Package**

Marking and pin assignment



TO220 top view



Schematic diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Quantity
70N10	S70N10T	TO220	50

Absolute Maximum Ratings ($T_C=25^{\circ}\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	$I_D@T_C = 25^{\circ}\text{C}$	70	A
	$I_D@T_C = 100^{\circ}\text{C}$	45	A
Pulsed Drain Current ¹	I_{DM}	280	A
Single Pulsed Avalanche Energy ²	E_{AS}	110	mJ
Avalanche Current	I_{AS}	-	A
Power Dissipation	P_D	100	W
Operating Junction Temperature Range	T_J	150	$^{\circ}\text{C}$
Storage Temperature Range	T_{STG}	-55 ~ 150	$^{\circ}\text{C}$

Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	64	$^{\circ}\text{C/W}$
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.25	$^{\circ}\text{C/W}$



Ordering Information

Ordering Number	Package	Pin Assignment			Packing
Halogen Free		G	D	S	
HLS70N10T	TO220	1	2	3	Tube

Electrical Characteristics ($T_A=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain to Source Breakdown Voltage	V_{DS}	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	100	-	-	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=100\text{V}$, $V_{GS}=0\text{V}$	-	-	1	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	-	-	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}$, $I_D = 250\mu\text{A}$	1.3	1.8	2.3	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}$, $I_D=20\text{A}$	-	8.5	10.5	m Ω
		$V_{GS}=4.5\text{V}$, $I_D=15\text{A}$	-	9.5	15	
Gate Resistance	R_g	$V_{GS}=0\text{V}$, V_{DS} Open	-	0.48	-	Ω
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}$, $V_{DS}=50\text{V}$, $f = 1\text{MHz}$	-	1368	-	pF
Output Capacitance	C_{oss}		-	451	-	
Reverse Transfer Capacitance	C_{rss}		-	12.9	-	
Total Gate Charge	Q_g	$V_{GS}=10\text{V}$, $V_{DS}=50\text{V}$, $I_D=10\text{A}$	-	31.3	-	nC
Gate Source Charge	Q_{gs}		-	3.49	-	
Gate Drain Charge	Q_{gd}		-	7.63	-	
Turn-ON Delay Time	$t_{d(on)}$	$V_{GS}=10\text{V}$, $V_{DS}=50\text{V}$, $I_D=10\text{A}$, $R_G=4\Omega$	-	16	-	ns
Rise Time	t_r		-	10	-	
Turn-OFF Delay Time	$t_{d(off)}$		-	40	-	
Fall Time	t_f		-	6	-	
Diode Forward Current	I_S	$T_C=25^{\circ}\text{C}$	-	-	70	A
Diode Forward Voltage	V_{SD}	$I_S=10\text{A}$, $V_{GS}=0\text{V}$	-	-	1.2	V
Reverse Recovery time	t_{rr}	$I_S=10\text{A}$, $V_{DD}=50\text{V}$, $dI/dt=100\text{A}/\mu\text{s}$	-	103	-	ns
Reverse Recovery Charge	Q_{rr}		-	187	-	nC

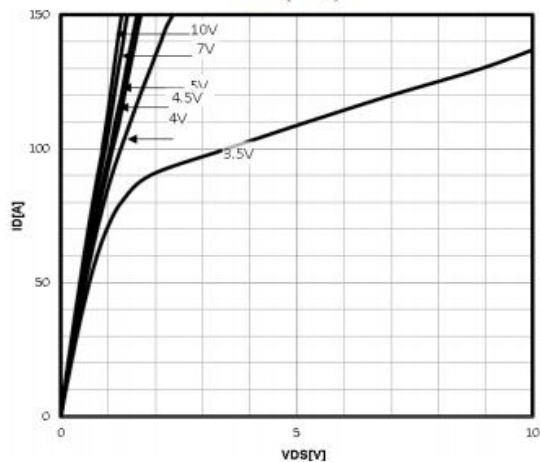
Notes:

- 1.Repetitive rating; pulse width limited by maximum junction temperature.
2. $V_{DD}=50\text{V}$, $L=0.3\text{mH}$, $R_g=25\Omega$, Starting $T_J=25^{\circ}\text{C}$.

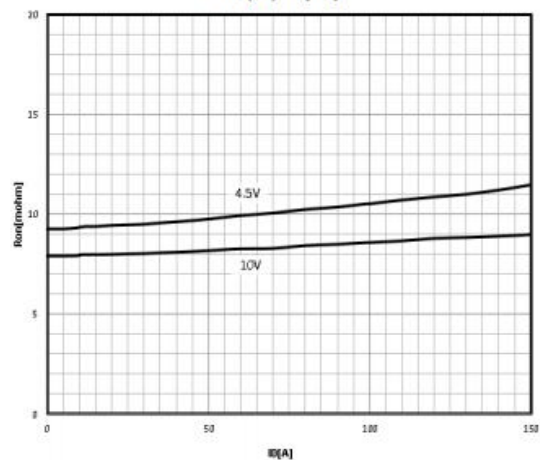


Typical Performance Characteristics

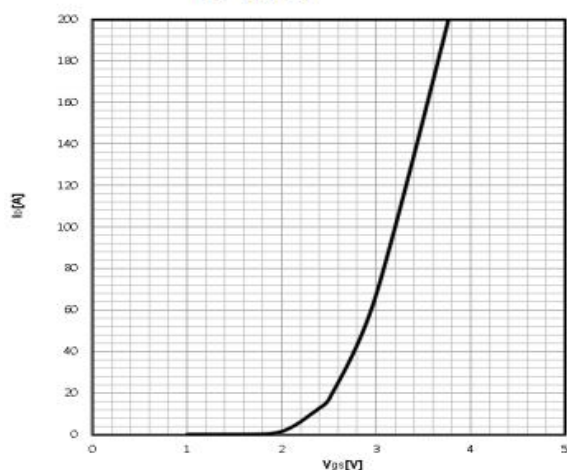
Typ. output characteristics
 $I_D = f(V_{DS})$



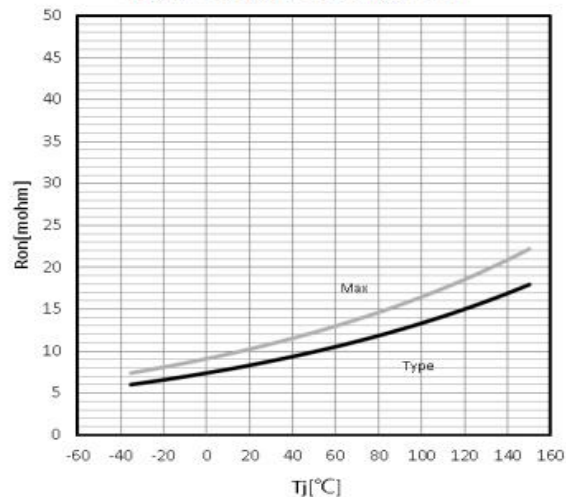
Typ. drain-source on resistance
 $R_{DS(on)} = f(I_D)$



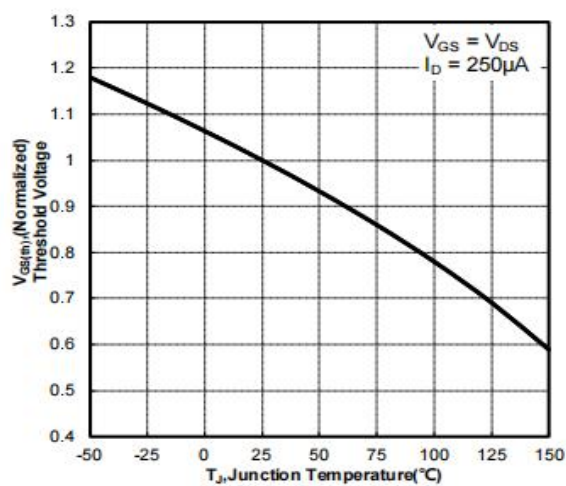
Typ. transfer characteristics
 $I_D = f(V_{GS})$



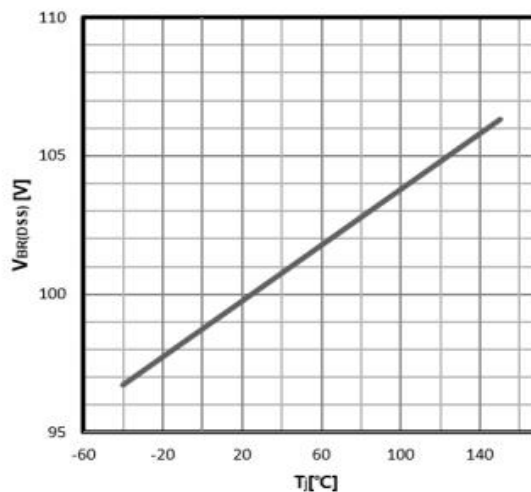
Drain-source on-state resistance
 $R_{DS(on)} = f(T_J); I_D = 20A; V_{GS} = 10V$



Gate Threshold Voltage
 $V_{TH} = f(T_J); I_D = 250\mu A$

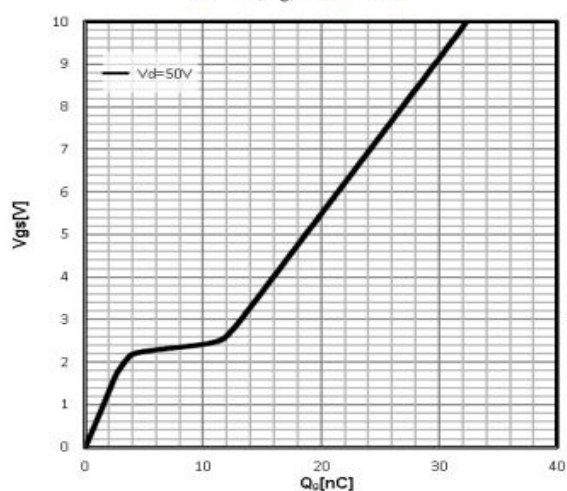


Drain-source breakdown voltage
 $V_{BR(DSS)} = f(T_J); I_D = 250\mu A$

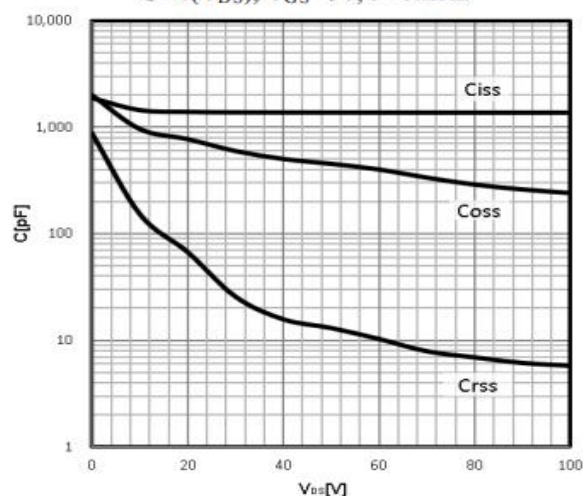




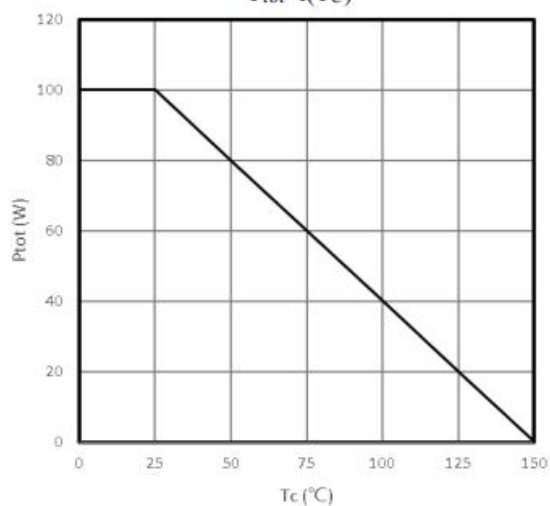
Typ. gate charge
 $V_{GS}=f(Q_g); I_D=10A$



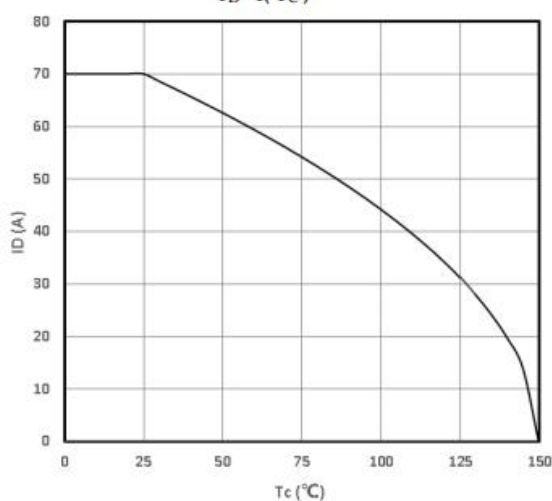
Typ. capacitances
 $C=f(V_{DS}); V_{GS}=0V; f=1MHz$



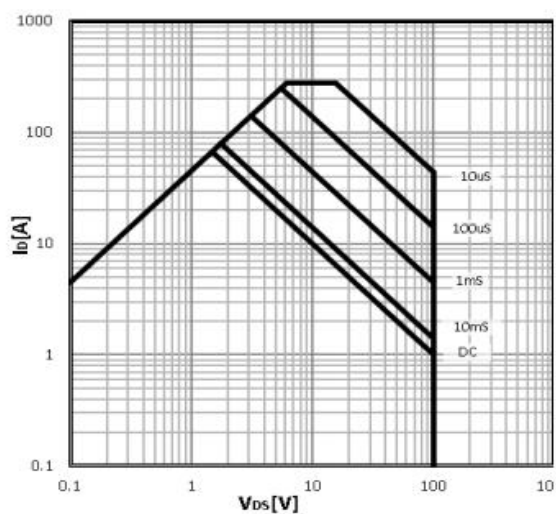
Power Dissipation
 $P_{tot}=f(T_c)$



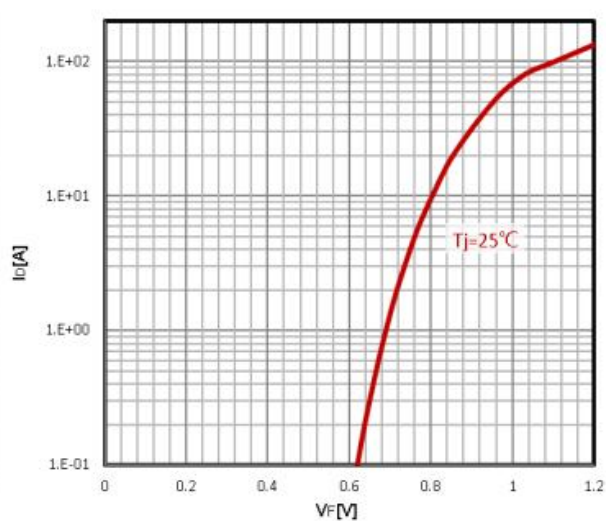
Maximum Drain Current
 $I_D=f(T_c)$



Safe operating area
 $I_D=f(V_{DS})$

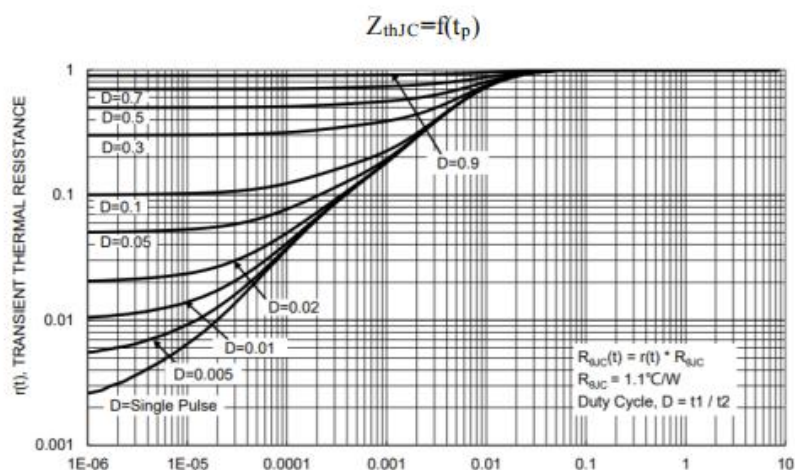


Body Diode Forward Voltage Variation
 $I_F=f(V_{GS})$

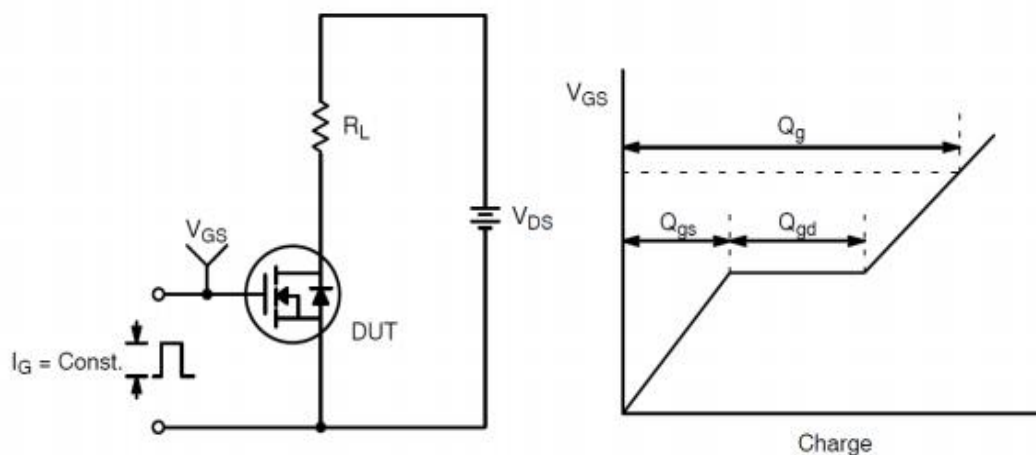




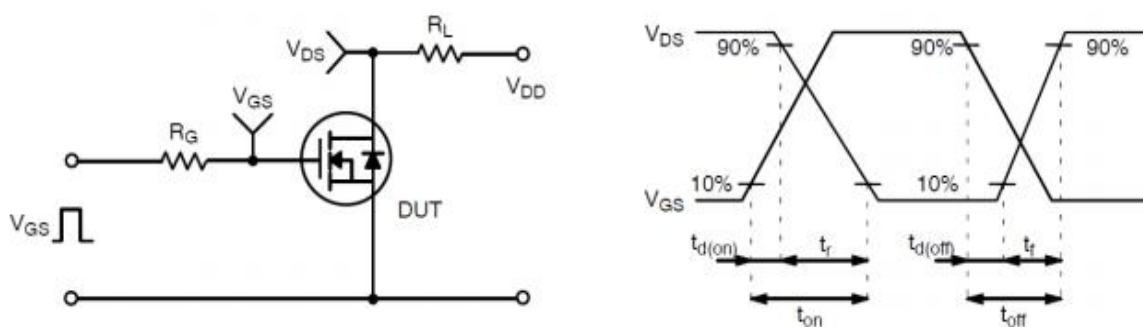
Max. transient thermal impedance



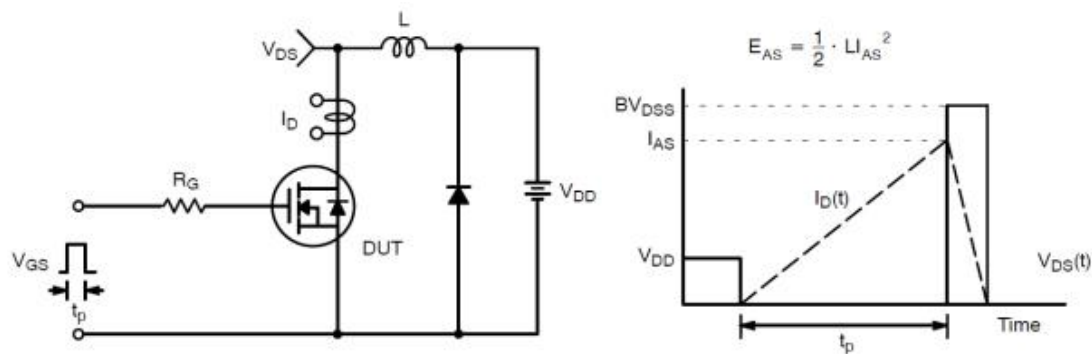
Test Circuit and Waveform



Gate Charge Test Circuit & Waveform

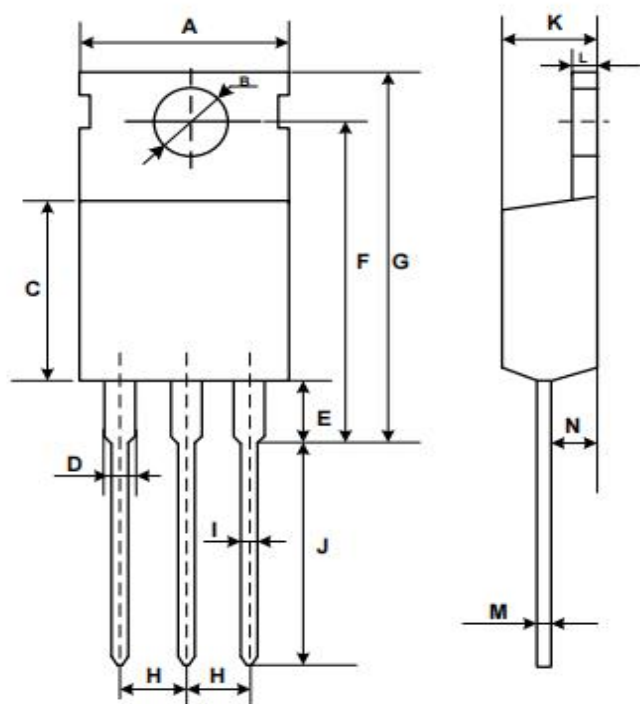


Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

Package Dimensions TO220



SYMBOL	MM	
	MIN	MAX
A	9.70	10.30
B	3.40	3.80
C	8.80	9.40
D	1.17	1.47
E	2.60	3.50
F	15.10	16.70
G	19.55MAX	
H	2.54REF	
I	0.70	0.95
J	9.35	11.00
K	4.30	4.77
L	1.20	1.45
M	0.40	0.65
N	2.20	2.60



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